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EUV and X-ray Optics, Sources, and Instrumentation

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Contents

ASTRONOMICAL X-RAY OPTICS

- 11776 05 **Lobster eye type X-ray telescope with chromium-iridium coated tri-layer mirrors** [11776-1]
- 11776 06 **Mirrors for space telescopes: degradation issues** [11776-2]
- 11776 07 **Characterisation of X-ray mirrors based on chromium-iridium tri-layer coatings** [11776-3]
- 11776 08 **X-ray testing of the multifoil optical system REX II for rocket experiment** [11776-4]

MULTILAYER X-RAY OPTICS AND INTERFEROMETRY

- 11776 09 **X-ray interferometry technique for thin-films study using a microfocus laboratory source**
[11776-5]
- 11776 0A **Thin layer imaging approach by X-ray amplitude splitting interferometer based on compound refractive lens** [11776-6]

LABORATORY X-RAY/EUV OPTICS

- 11776 0D **Laboratory complex for the tests of the X-ray optics and coherence-related techniques**
[11776-9]
- 11776 0E **Celebrating the Röntgen anniversary year: pupil experiments at Aschaffenburg University**
[11776-10]

REFRACTIVE AND DIFFRACTIVE X-RAY OPTICS

- 11776 0G **Synthetic single crystal diamonds for X-ray optics** [11776-12]
- 11776 0I **X-ray refractive glass microlenses produced by ion beam lithography** [11776-14]

INTRODUCTION, FACILITIES AND FEL SOURCES

- 11776 0M **Options for high-repetition-rate seeded FEL** [11776-17]

DIAGNOSTICS METHODS FOR FEL OPERATION AND EXPERIMENTS

11776 OR **A XUV and soft X-ray split-and-delay unit for FLASH2** [11776-26]

DAMAGE TO OPTICAL ELEMENTS

11776 OV **Damage study on B₄C films using a table-top nanosecond EUV damage instrument** [11776-24]

11776 OW **Photoinduced defects in Er/Al-doped optical fiber** [11776-25]